

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/534,048	TERADA, YUICHI	
Examiner		Art Unit		Page 1 of 1
Mohammad M. Ali		3744		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0029583	03-2002	Chung et al.	62/428
*	B	US-2002/0144513	10-2002	Gunji et al.	62/263
*	C	US-5,445,214	08-1995	Han, Guen-Pil	165/11.1
*	D	US-5,341,650	08-1994	Nagasawa et al.	62/180
*	E	US-3,741,290	06-1973	Nenadal, Clarence G.	165/48.1
*	F	US-5,055,115	10-1991	Yikai et al.	96/59
*	G	US-5,332,425	07-1994	Huang, Ping	96/26
*	H	US-4,541,847	09-1985	Oie et al.	96/58
*	I	US-5,678,417	10-1997	Nigo et al.	62/186
*	J	US-6,477,854	11-2002	Chung et al.	62/280
*	K	US-6,557,364	05-2003	Gunji et al.	62/263
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 200-28156 A	01-2000	Japan	Shunichi et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.